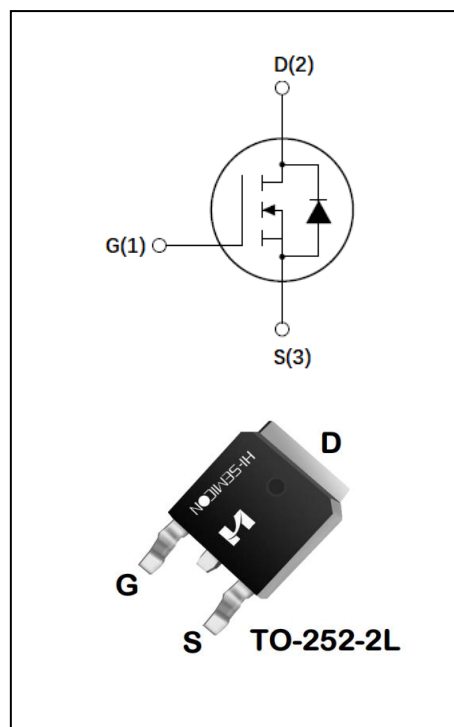


150A,30V N-CHANNEL MOSFET**GENERAL DESCRIPTION**

The SFD3015T uses advanced trench technology and design to provide excellent $R_{DS(on)}$ with low gate charge. It can be used in a wide variety of applications. Such as: PWM Applications, Power Management, etc.

FEATURES

- ◆ $R_{DS(on)}=2.6m\Omega(Typ)@V_{GS}=10V$
- ◆ $R_{DS(on)}=4.1m\Omega(Typ)@V_{GS}=4.5V$
- ◆ $V_{DS}=30V, I_D=150A$
- ◆ Low C_{rss} : $320pF(Typ)@V_{DS}=25V$
- ◆ Advance Trench Technology
- ◆ Fast Switching and High efficiency
- ◆ Lead Free and Green Devices Available: RoHS Compliant

**ORDERING INFORMATION**

Part No.	Package	Marking	Material	Packing
SFD3015T	TO-252-2L	SFD3015T	Pb Free	Reel

ABSOLUTE MAXIMUM RATINGS ($T_C=25^{\circ}\text{C}$ unless otherwise noted)

Characteristics	Symbol	Ratings	Unit
Drain-Source Voltage	V_{DS}	30	V
Gate-Source Voltage	V_{GS}	± 20	V
Drain Current	I_D	$T_C = 25^{\circ}\text{C}$	A
		$T_C = 100^{\circ}\text{C}$	
Drain Current Pulsed(Note 1)	I_{DM}	400	A
Power Dissipation($T_C=25^{\circ}\text{C}$)	P_D	115	W
Single Pulsed Avalanche Energy (Note 2)	E_{AS}	663	mJ
Operation Junction Temperature Range	T_J	$-55\sim+175$	$^{\circ}\text{C}$
Storage Temperature Range	T_{stg}	$-55\sim+175$	$^{\circ}\text{C}$

THERMAL CHARACTERISTICS

Characteristics	Symbol	MAX	Unit
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	1.5	$^{\circ}\text{C/W}$
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	62.5	$^{\circ}\text{C/W}$

ELECTRICAL CHARACTERISTICS

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Off Characteristics						
Drain -Source Breakdown Voltage	B _{VDSS}	V _{GS} =0V, I _D =250μA	30	--	--	V
Drain-Source Leakage Current	I _{DSS}	V _{DS} =30V, V _{GS} =0V	--	--	1.0	μA
Gate-Source Leakage Current	I _{GSS}	V _{GS} =20V, V _{DS} =0V	--	--	100	nA
Gate-Source Leakage Current	I _{GSS}	V _{GS} =-20V, V _{DS} =0V	--	--	-100	nA
On Characteristics						
Gate Threshold Voltage	V _{GS(th)}	V _{GS} = V _{DS} , I _D =250μA	1.0	--	2.5	V
Static Drain- Source On State Resistance(Note 3)	R _{DS(on)}	V _{GS} =10V, I _D =30A	--	2.6	3.0	mΩ
		V _{GS} =4.5V, I _D =20A	--	4.1	6.0	
Forward Transconductance	g _{FS}	V _{DS} =5V, I _D =10A	--	26	--	s
Dynamic Characteristics						
Input Capacitance	C _{iss}	V _{DS} =25V V _{GS} =0V f=1.0MHZ	--	3210	--	pF
Output Capacitance	C _{oss}		--	333	--	
Reverse Transfer Capacitance	C _{rss}		--	320	--	
Total Gate Charge	Q _g	V _{DS} =15V I _D =30A V _{GS} =10V	--	72	--	nC
Gate-Source Charge	Q _{gs}		--	13	--	
Gate-Drain Charge	Q _{gd}		--	17	--	
Switching Characteristics						
Turn-on Delay Time	t _{d(on)}	V _{DS} =15V,V _{GS} =4.5V R _G =1.8Ω,I _D =60A	--	15	--	ns
Turn-on Rise Time	t _r		--	125	--	
Turn-off Delay Time	t _{d(off)}		--	40	--	

Turn-off Fall Time	t_f	$V_{DS}=15V, V_{GS}=4.5V$ $R_G=1.8\Omega, I_D=60A$	--	88	--	ns
--------------------	-------	---	----	----	----	----

SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Continuous Source Current	I_S	Integral Reverse P-N Junction Diode in the MOSFET	--	--	150	A
Pulsed Source Current	I_{SM}		--	--	400	
Diode Forward Voltage	V_{SD}	$I_S=20A, di/dt=100A/\mu S$	--	--	1.2	V

Notes:

1. Pulse width limited by maximum junction temperature

2. $L=0.5mH$, $V_G=10V$, $R_G=25\Omega$, starting $T_J=25^\circ C$

3. Pulse Test: Pulse width $\leq 300\mu s$, Duty cycle $\leq 2\%$;

Typical Performance Characteristics

Figure1: Output Characteristics

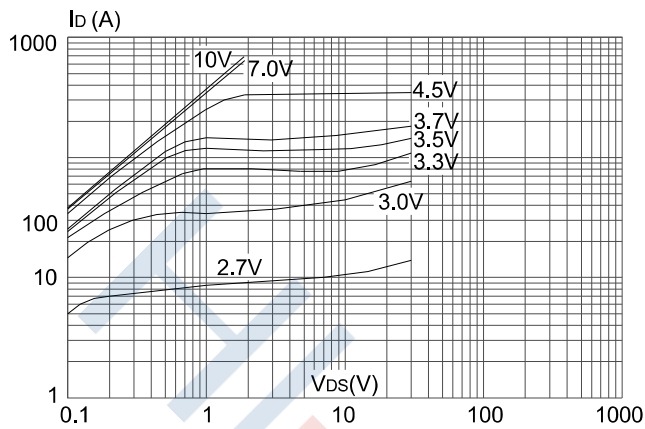


Figure 2: Typical Transfer Characteristics

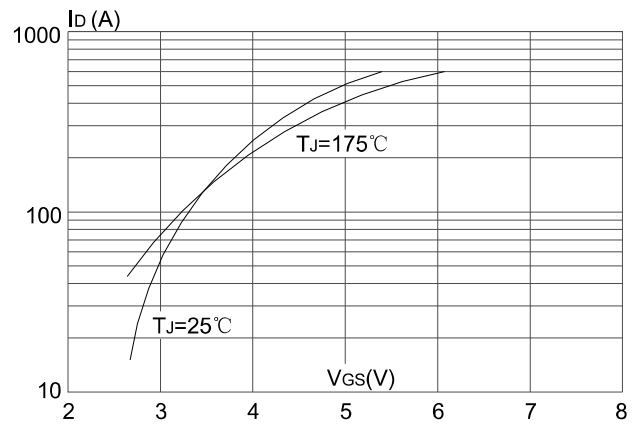


Figure 3: On-resistance vs. Drain Current

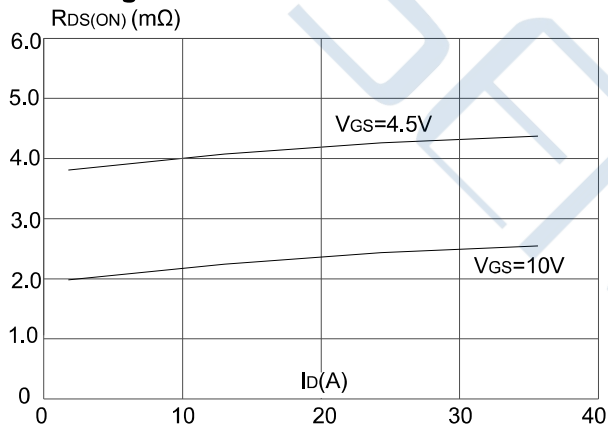


Figure 4: Body Diode Characteristics

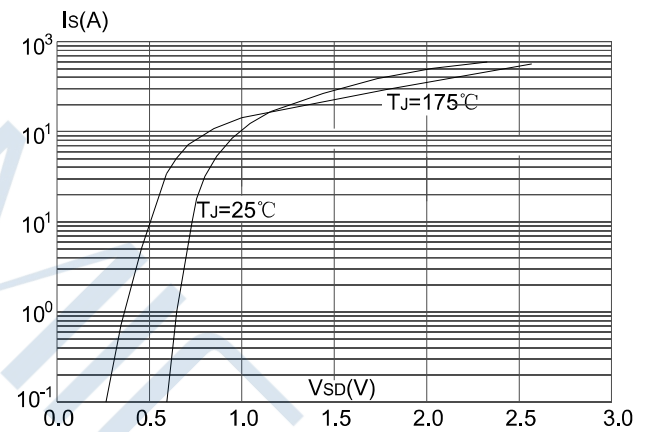


Figure 5: Gate Charge Characteristics

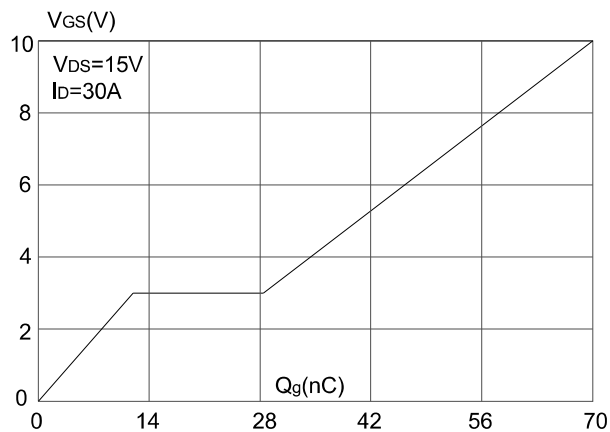
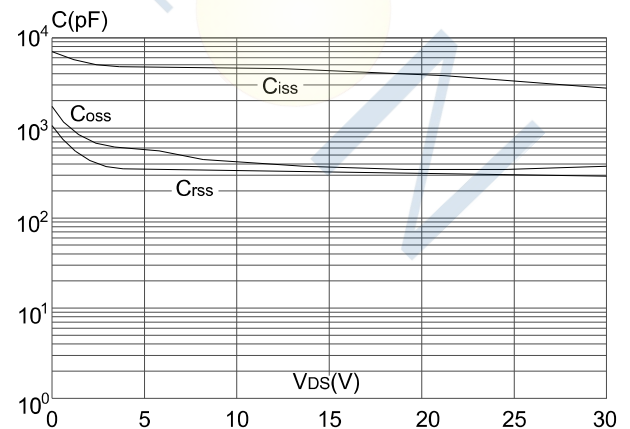


Figure 6: Capacitance Characteristics



Typical Performance Characteristics

Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

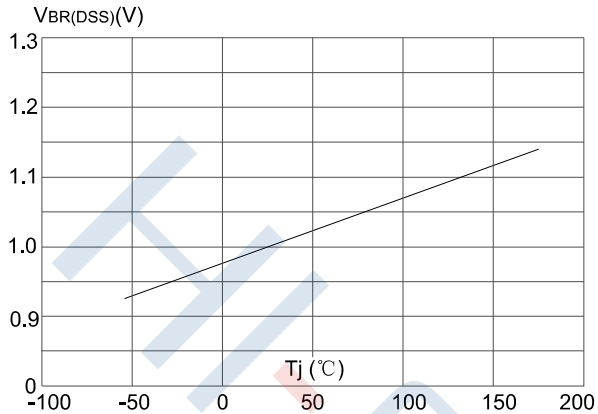


Figure 8: Normalized on Resistance vs. Junction Temperature

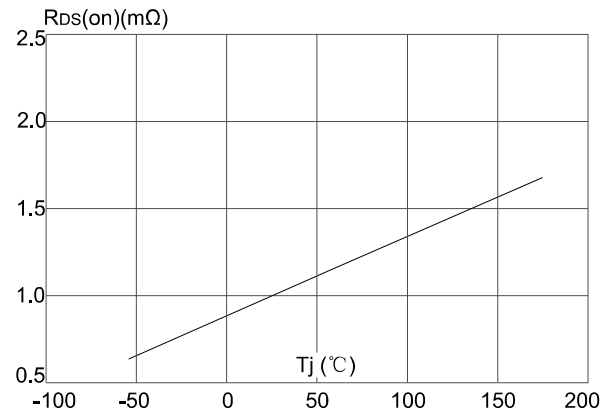


Figure 9: Maximum Safe Operating Area

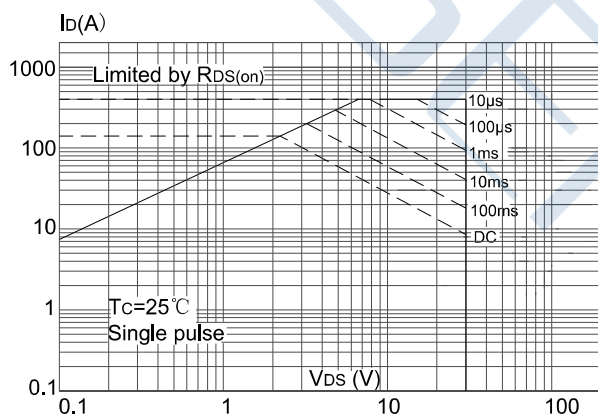


Figure 10: Maximum Continuous Drain Current vs. Case Temperature

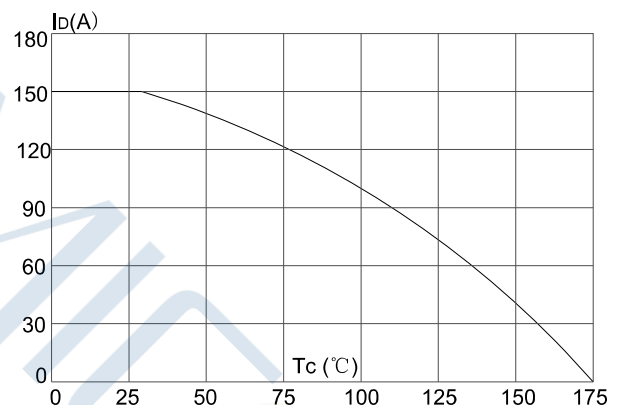
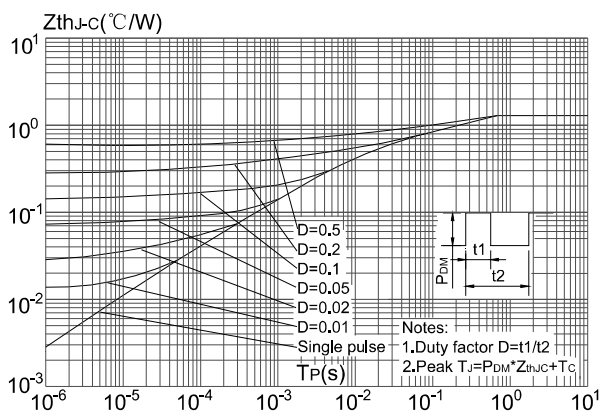


Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Case (TO-252)



Test Circuit

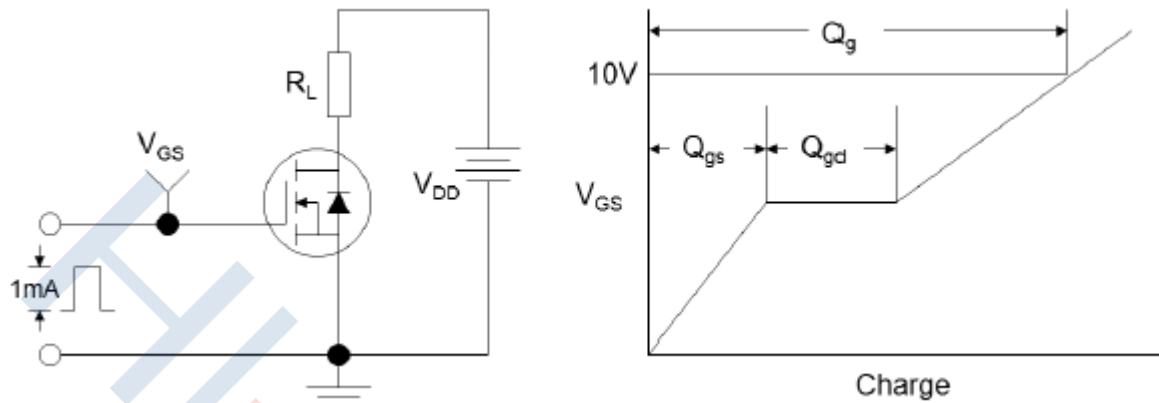


Figure1:Gate Charge Test Circuit & Waveform

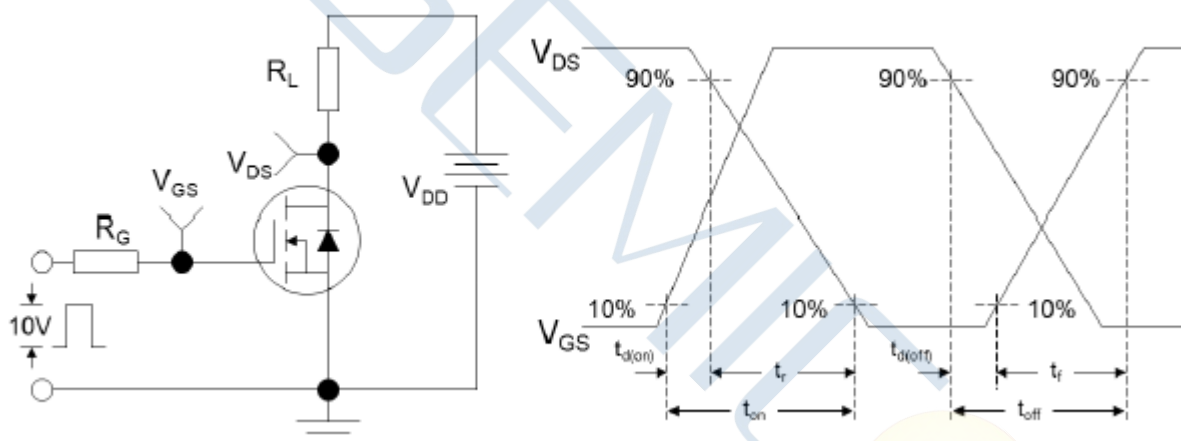


Figure 2: Resistive Switching Test Circuit & Waveforms

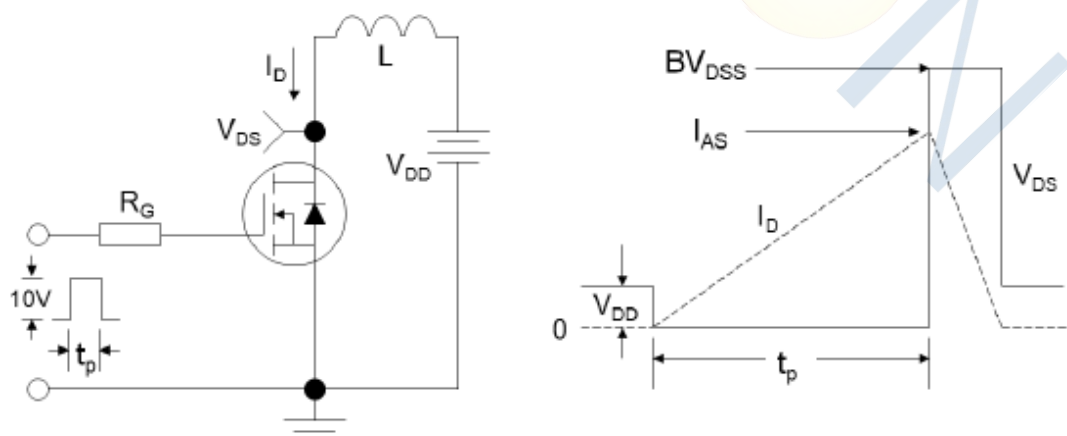


Figure 3:Unclamped Inductive Switching Test Circuit & Waveforms

Test Circuit

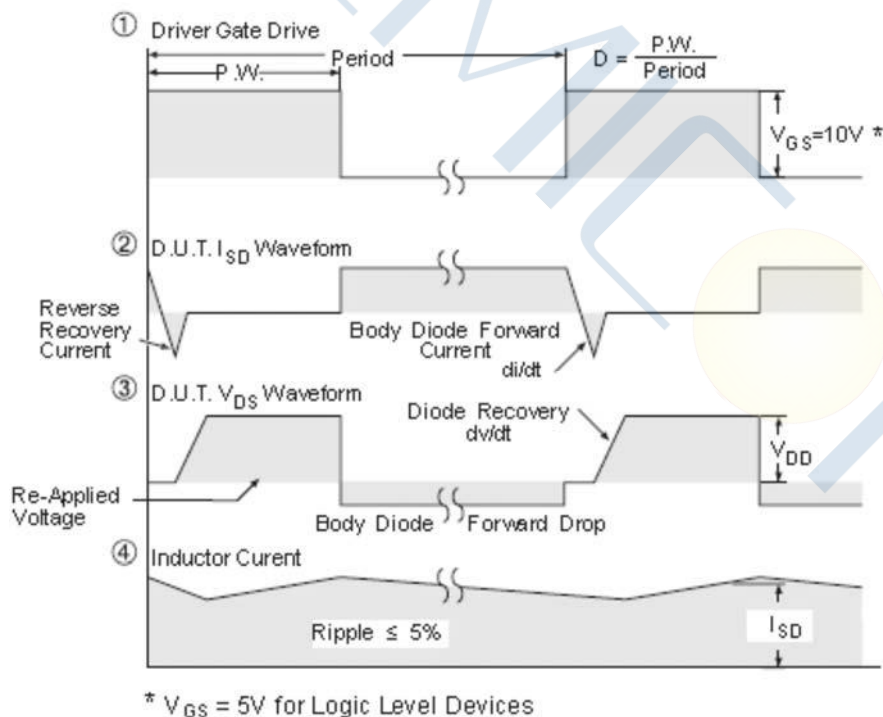
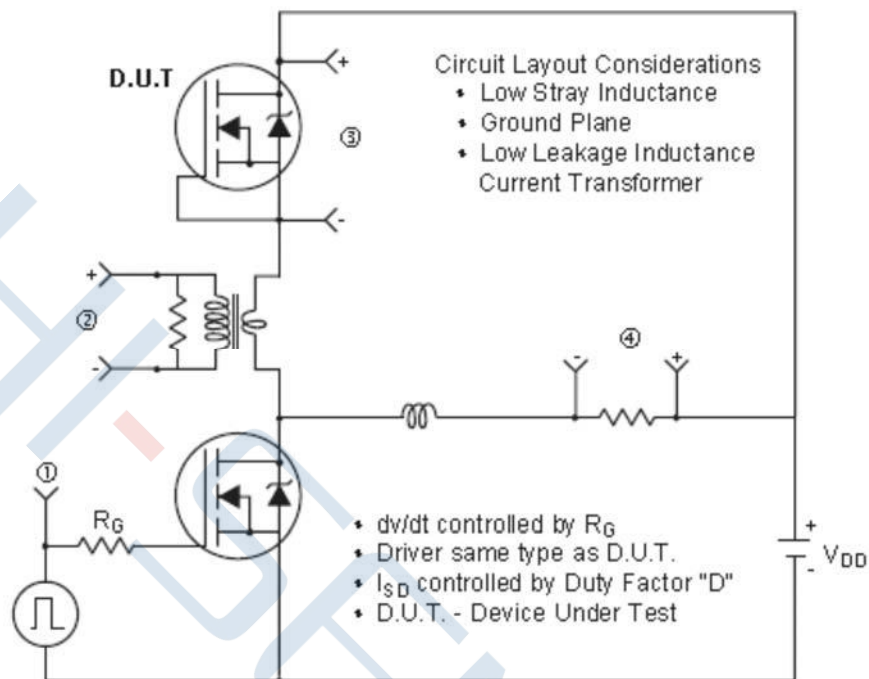
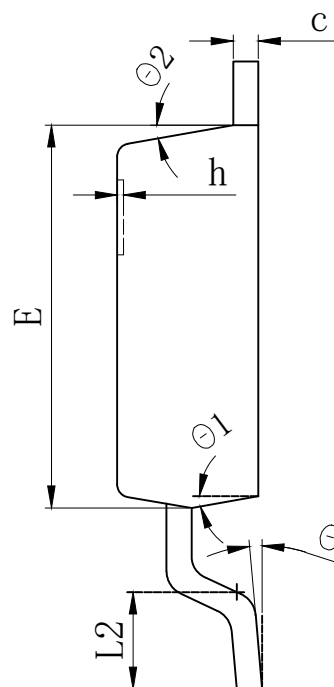
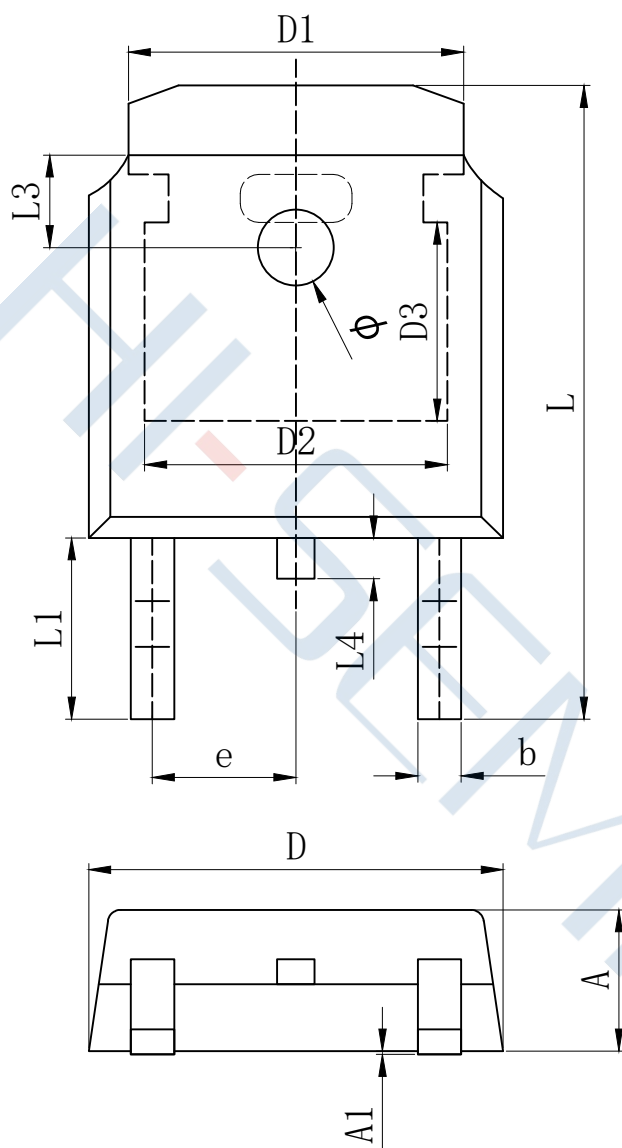


Figure 4: Peak Diode Recovery dv/dt Test Circuit & Waveforms (For N-channel)

Package Dimensions of TO-252-2L

Unit:mm



SYMBOL	MILLIMETER		
	MIN	Typ.	MAX
A	2.200	2.300	2.400
A1	0.000		0.127
b	0.640	0.690	0.740
c(电镀后)	0.460	0.520	0.580
D	6.500	6.600	6.700
D1	5.334 REF		
D2	4.826 REF		
D3	3.166 REF		
E	6.000	6.100	6.200
e	2.286 TYP		
h	0.000	0.100	0.200
L	9.900	10.100	10.300
L1	2.888 REF		
L2	1.400	1.550	1.700
L3	1.600 REF		
L4	0.600	0.800	1.000
Φ	1.100	1.200	1.300
θ	0°		8°
θ 1	9° TYP		
θ 2	9° TYP		

Disclaimer:

- ▶ Hi-semicon reserves the right to make changes to the information herein for the improvement of the design and performance without further notice! Customers should obtain the latest relevant information before placing orders and should verify that such information is complete and current.
- ▶ All semiconductor products malfunction or fail with some probability under special conditions. When using Hi-semicon products in system design or complete machine manufacturing, it is the responsibility of the buyer to comply with the safety standards strictly and take essential measures to avoid situations in which a malfunction or failure of such Hi-semicon products could cause loss of body injury or damage to property.
- ▶ Hi-semicon will supply the best possible product for customers!